

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,949,761 B2
APPLICATION NO. : 10/685013
DATED : September 27, 2005
INVENTOR(S) : Jack O. Chu et al.

Page 1 of 2

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title Page:

“(75) Jack O. Chu, Manhasset Hills, NY”

should read

-- (75) Jack O. Chu, Manhasset Hills, NY --

Column 9, Line 28, Claim 1:

“a Si cap layer on top of said top”

should read

-- a Si cap layer under tensile strain on top of said top --

Column 9, Line 47, Claim 3:

“between 2 to 20nm” should read -- between 2 nm to nm--

Column 10, Line 28, Claim 8:

“a Si cap layer on top of said top”

should read

-- a Si cap layer under tensile strain on top of said top --

Column 11, Line 33, Claim 17:

“a Si cap layer on top of said top”

should read

-- a Si cap layer under tensile strain on top of said top --

Column 13, Line 2, Claim 29:

“a Si cap layer on top of said top”

should read

-- a Si cap layer under tensile strain on top of said top --

Column 13, Line 46, Claim 34:

“a Si cap layer on top of said top”

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should read

-- a Si cap layer under tensile strain on top of said top --

Column 14, Line 44, Claim 41:
“a Si cap layer on top of said top”

should read

-- a Si cap layer under tensile strain on top of said top --

Column 15, Line 57, Claim 51:
“a Si cap layer on top of said top”

should read

-- a Si cap layer under tensile strain on top of said top --

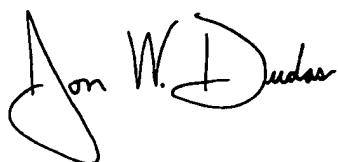
Column 16, Line 61, Claim 58:
“a Si cap layer on top of said top”

should read

-- a Si cap layer under tensile strain on top of said top --

Signed and Sealed this

Eleventh Day of March, 2008



JON W. DUDAS
Director of the United States Patent and Trademark Office